

# SP9210

## 200MHz DUAL 4-BIT LATCH

The SP9210 is a dual 4-bit master/slave D-type flip-flop with asynchronous set and reset which override the clock input.

Data is entered into the master when the clock is low and is transferred to the slave on the positive transition of the clock, the device being edge-sensitive.

On-chip pulldown resistors eliminate the need to tie unused inputs to V<sub>EE</sub>.

### FEATURES

- Dual 4-Bit Master/Slave D-Type Flip-Flop
- Clock Rate in Excess of 200MHz
- -5.2V Supply
- Current Consumption Typically 145mA
- Input Current Less Than 330µA
- Operating Temperature Range -30°C to +85°C
- Set and Reset Inputs Provided
- ECL 10K Compatible
- Dual Clock Inputs

### ORDERING INFORMATION

- SP9210DG (Industrial - Ceramic DIL package)
- SP9210BB DG (Plessey High Reliability Ceramic DIL package)

### PIN NAMES

S1-4	Set input for 1-4
S5-8	Set input for 5-8
V <sub>EE</sub>	Supply voltage (-VE)
D1-8	Data inputs 1-8
CLK1-4	Clock latch for 1-4
CLK5-8	Clock latch for 5-8
Q1-8	Outputs latches 1-8
R1-4	Reset input latch for 1-4
R5-8	Reset input latch for 5-8

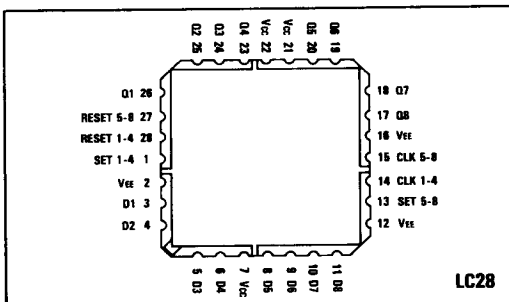


Fig.1(b) Pin connections, surface mounting package (top view)

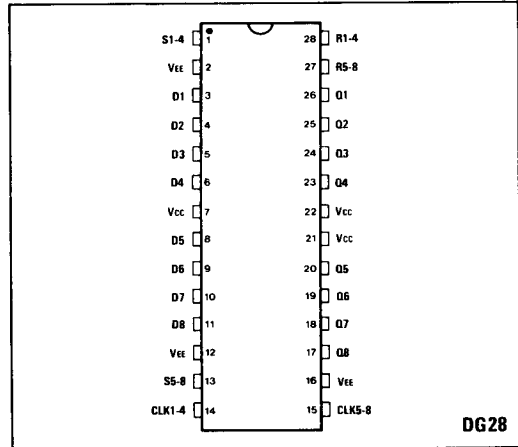


Fig.1(a) Pin connections, ceramic DIL package (top view)

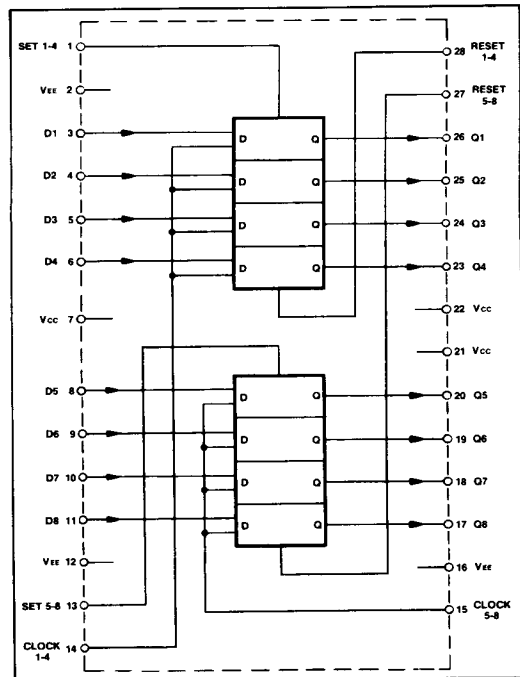


Fig.2 SP9210 block diagram

**ELECTRICAL CHARACTERISTICS**

Each circuit has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. Outputs are terminated through a 50 ohm resistor to -2 volts. Test procedures are shown for only one input and one output. The other inputs and outputs are tested in the same manner.

Characteristic	Symbol	Pin under test	-30°C		+25°C		+85°C		Unit	Test temp.	TEST VOLTAGES (V)				V <sub>CC</sub> (GND)		
			Min.	Max.	Min.	Typ.	Max.	Min.			Max.	V <sub>IH</sub> Max.	V <sub>IH</sub> Min.	V <sub>IL</sub> Min.		V <sub>IL</sub> Max.	V <sub>EE</sub>
			TEST VOLTAGE APPLIED TO PINS LISTED BELOW									V <sub>IH</sub> MAX.	V <sub>IH</sub> MIN.	V <sub>IL</sub> MAX.		V <sub>IL</sub> MIN.	V <sub>EE</sub>
<b>POWER SUPPLY</b>																	
Drain current	I <sub>EE</sub>	2,12,16	-	200	-	145	180	-	200	mA	-	-	-	2,12,16	7,21,22		
Input current	I <sub>INH</sub>	Set/Reset Clock	-	-	-	-	330	-	-	µA	-	-	-	2,12,16	7,21,22		
Input leakage current	I <sub>INL</sub>	Data	-	-	-	-	310	-	-	µA	-	-	-	2,12,16	7,21,22		
Logic '1' output voltage	V <sub>OH</sub>	All inputs All outputs	-	-	0.5	-	-	-	-	V	-	Note 1	-	2,12,16	7,21,22		
Logic '0' output voltage	V <sub>OL</sub>	All outputs (Note 2)	-1.06	-0.89	-0.96	-	-0.81	-0.89	-0.70	V	-	-	-	2,12,16	7,21,22		
Logic '1' threshold voltage	V <sub>OH1</sub>	All outputs (Note 2)	-1.89	-1.675	-1.85	-	-1.65	-1.825	-1.615	V	-	Data inputs	-	2,12,16	7,21,22		
Logic '0' threshold voltage	V <sub>OL1</sub>	All outputs (Note 2)	-1.08	-	-0.98	-	-	-0.91	-	V	-	-	-	2,12,16	7,21,22		
			-	-1.655	-	-	-1.63	-	-1.595	V	-	-	Data inputs	-	7,21,22		
<b>SWITCHING TIMES</b>																	
Clock input propagation delay	t <sub>p+</sub>	All outputs	1.0	3.0	1.0	2.0	3.0	1.1	3.4	ns	+1.11V Data inputs	+0.3V	Pulse in Clock inputs	Pulse out Outputs	-2.0V 7,21,22		
Rise time (20% - 80%)	t <sub>r</sub>	All outputs	1.0	3.0	1.0	2.0	3.0	1.1	3.4	ns	-	Data inputs	Clock inputs	Outputs	7,21,22		
Fall time (20% - 80%)	t <sub>f</sub>	All outputs	1.0	3.0	1.0	2.0	3.0	1.1	3.3	ns	Data inputs	-	Clock inputs	Outputs	7,21,22		
Set propagation delay	t <sub>set</sub>	All outputs	1.0	3.0	1.0	2.0	3.0	1.1	3.3	ns	-	Data inputs	Clock inputs	Outputs	7,21,22		
Reset propagation delay	t <sub>reset</sub>	All outputs	1.5	4.0	1.5	2.5	4.0	1.4	4.5	ns	-	-	Set inputs Reset inputs	Outputs	7,21,22		
Set up time	t <sub>s</sub>	Data inputs	1.5	-	1.5	-	-	1.5	-	ns	-	-	Clock inputs	Outputs	7,21,22		
Hold time	t <sub>h</sub>	Data inputs	1.0	-	1.0	-	-	1.0	-	ns	-	-	Data, Clock inputs	Outputs	7,21,22		
Max. clock frequency	f <sub>CLK</sub>	All outputs	-	-	200	-	-	1.0	-	MHz	Data inputs	-	Clock inputs	Outputs	7,21,22		



NOTES  
 1. Each input pin tested individually.  
 2. Output level to be measured after a clock pulse has been applied.

Thermal characteristics  
 DG28 θ<sub>JA</sub> = 40°C/W  
 θ<sub>JC</sub> = 15°C/W  
 LC28 θ<sub>JA</sub> = 70°C/W  
 θ<sub>JC</sub> = 16°C/W

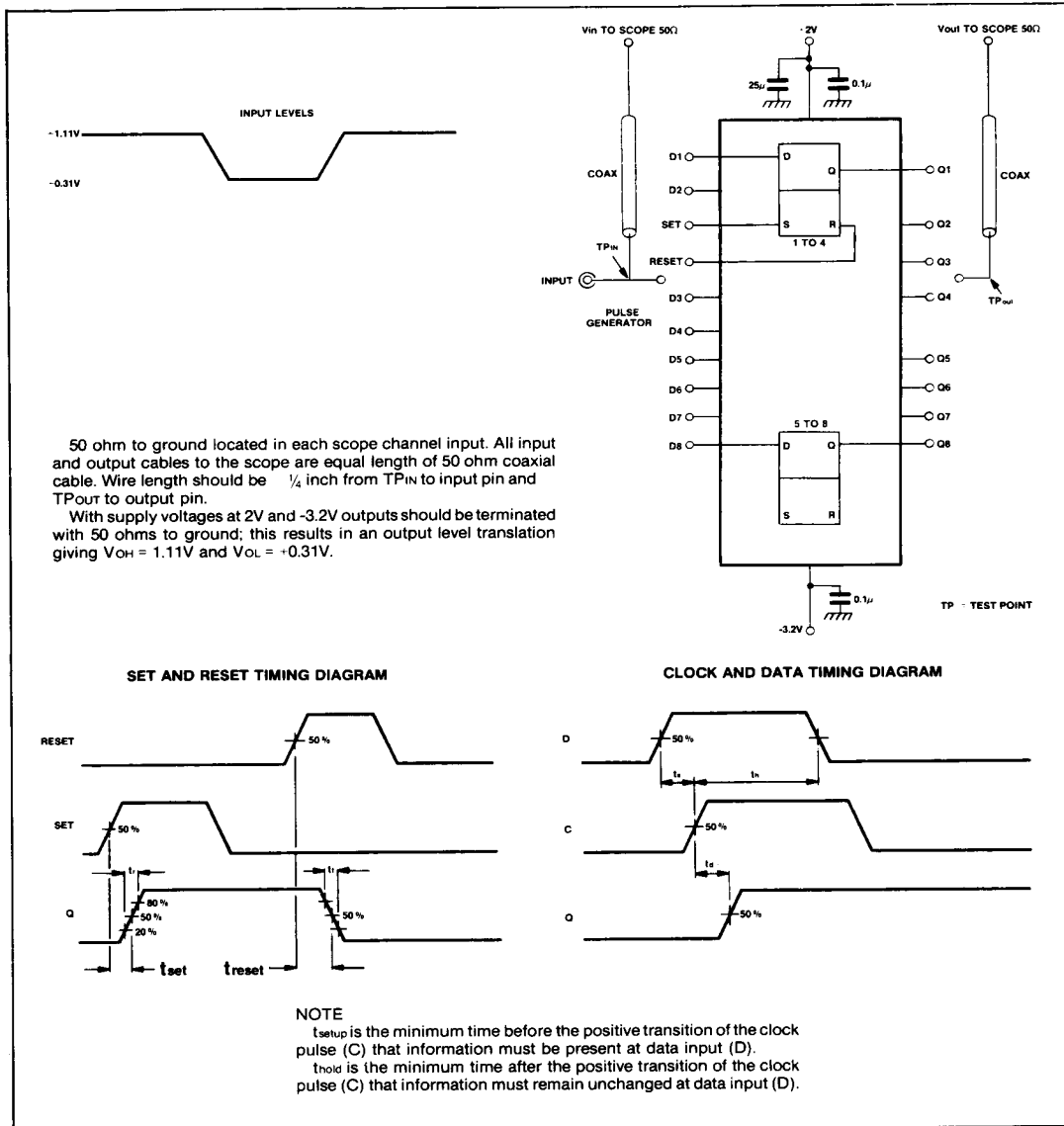


Fig.3 Test circuit details for dynamic test

**R - S TRUTH TABLE**

R	S	Q <sub>n</sub> + 1
L	L	Q <sub>n</sub>
L	H	H
H	L	L
H	H	ND

R = Reset, S = Set,  
 ND = Not defined

**CLOCKED TRUTH TABLE**

C	D	Q <sub>n</sub> + 1
L	X	Q <sub>n</sub>
↑	L	L
↑	H	H

C = Clock, D = Data,  
 ↑ = Rising edge,  
 X = Don't care

**ABSOLUTE MAXIMUM RATINGS**

Power supply voltage  
 Input voltages  
 Output source current  
 Storage temperature range  
 Junction operating temperature

|V<sub>CC</sub> - V<sub>EE</sub>| 7V  
 V<sub>CC</sub> to V<sub>EE</sub>  
 < 40mA  
 -65°C to +150°C  
 < 175°C

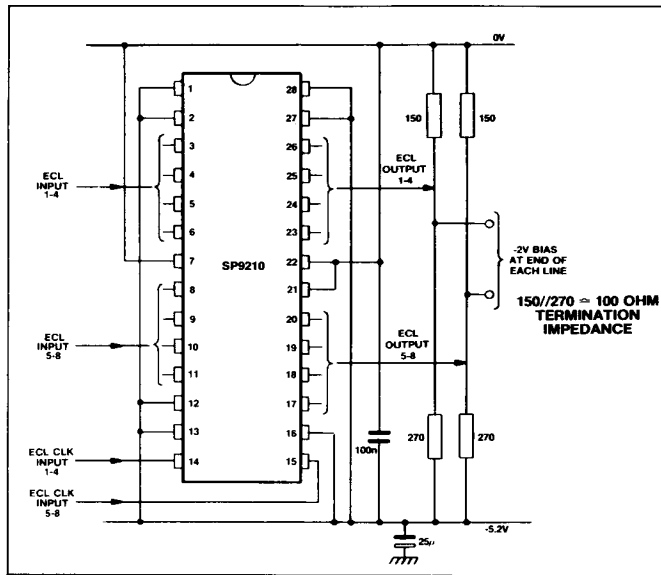


Fig.4 ECL 4 + 4 latch with 100Ω output termination